

Aerated concrete microwave reflection and transmission properties in a wet environment

Koppel, Tarmo; Vilcane, Inese; Mironovs, Viktors; Shishkin, Andrei; Rubene, Sanita; **Tint, Piia** Vide. Tehnologija. Resursi : XI starptautiskas zinatniski praktiskas konferences materiali 2017. gada 15.-17. junijs. 3. sejums = Environment. Technology. Resources : proceedings of the 11th International Scientific and Practical Conference. Volume III 2017 / p. 145-149 : ill <https://doi.org/10.17770/etr2017vol3.2619>

Computer aided method for measurement of reflection and impedance characteristics of RF devices

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Influence of parameters of pre-cataclysmic binaries on their light curves

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Londonisse kavandatakse ilma varjuta kõrghoonepaari. Päikese peegeldamine nõuab ettevaatust

Päikese peegeldamine nõuab ettevaatust

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Microwave reflection and absorption properties of wet snow

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Varjas, Toivo 2021 https://www.ester.ee/record=b5473279*est <https://digikogu.taltech.ee/et/Item/8a29147b-e21f-4273-aa1e-424bce74d20e> <https://doi.org/10.23658/taltech.60/2021>

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Snow microwave reflection at mobile phone frequency bands

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Temperature dependent electreflectance study of CdTe solar cells

Raadik, Taavi; Krustok, Jüri; Josepson, Raavo; Hiie, Jaan; Potlog, Tamara; **Spalatu, Nicolae** Thin solid films 2013 / p. 279-282 : ill <https://doi.org/10.1016/j.tsf.2012.12.083> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

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